Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/875,364	LEE ET AL.	
Examiner	Art Unit	
Khanh Tran	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	354	04/02/2006	кст
			:

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	257,259	4/2/2006	кст
	285,355		
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354,371 370 503,508 333 144,152,156 327 152-153,158,161			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Update Inventor Name Search	4/2/2006	кст
Updated Inventor Name Search		